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09/891,511	06/27/2001 RULE	438	2812	010819

## APPLICANTS

Mamoru Nakasuji, Kanagawa, JAPAN;  
Nobuharu Noji, Kanagawa, JAPAN;  
Tohru Satake, Kanagawa, JAPAN;  
Masahiro Hatakeyama, Kanagawa, JAPAN;  
Toshifumi Kimba, Kanagawa, JAPAN;  
Hiroshi Sobukawa, Kanagawa, JAPAN;  
Shoji Yoshikawa, Tokyo, JAPAN;  
Takeshi Murakami, Tokyo, JAPAN;  
Kenji Watanabe, Kanagawa, JAPAN;  
Tsutomu Karimata, Kanagawa, JAPAN;  
Shin Oowada, Kanagawa, JAPAN;  
Mutsumi Saito, Kanagawa, JAPAN;  
Yuichiro Yamazaki, Tokyo, JAPAN;  
Takamitsu Nagai, Kanagawa, JAPAN;  
Ichirota Nagahama, Kanagawa, JAPAN;

\*\* CONTINUING DATA ..... *none* *8/8*

\*\* FOREIGN APPLICATIONS .....

JAPAN 2000-193104 06/27/2000  
JAPAN 2000-229101 07/28/2000  
JAPAN 2000-335934 11/02/2000  
JAPAN 2001-11218 01/19/2001  
JAPAN 2001-31901 02/08/2001  
JAPAN 2001-31906 02/08/2001  
JAPAN 2001-33599 02/09/2001  
JAPAN 2001-35069 02/13/2001  
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JAPAN 2001-162041 05/30/2001  
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IF REQUIRED, FOREIGN FILING LICENSE GRANTED

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Foreign Priority claimed	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY	SHEETS DRAWING	TOTAL CLAIMS	INDEPENDENT CLAIMS
35 USC 119 (a-d) conditions met	<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Not after Allowance	JAPAN	50	60	13
Verified and Acknowledged	<i>Paul R. Brennan</i> Examiner's Signature				

ADDRESS

23850

TITLE

Inspection system by charged particle beam and method of manufacturing devices using the system

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